Redox Properties of Mixed Methyl/Vinylferrocenyl Monolayers on Si(111) Surfaces

Judith R. C. Lattimer, Bruce S. Brunschwig, Nathan S. Lewis*, and Harry B. Gray**

Kavli Nanoscience Institute and Beckman Institute Molecular Materials Research Center

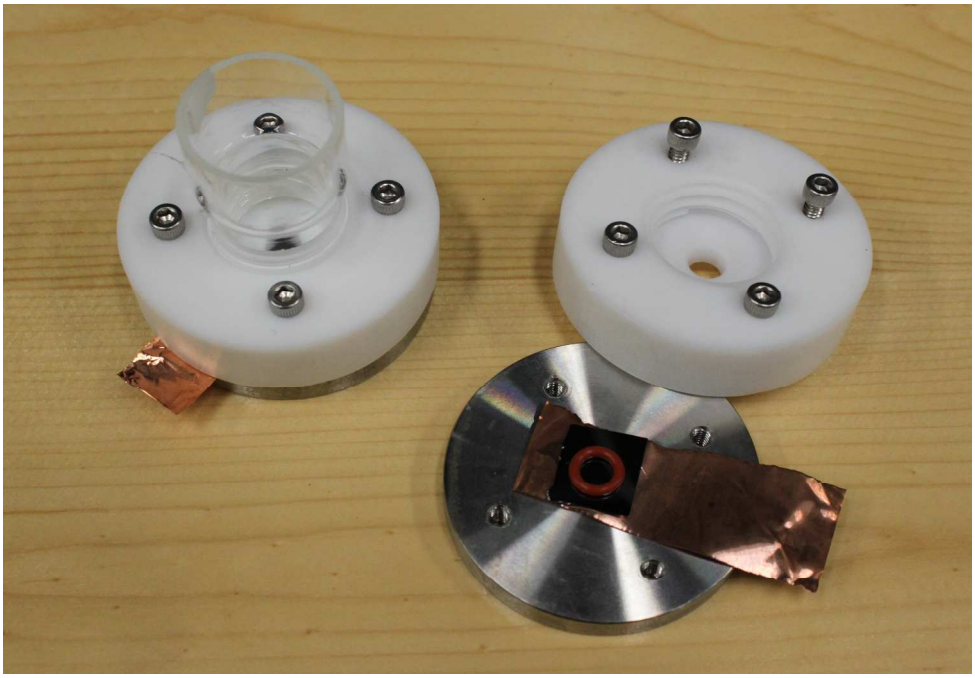
Division of Chemistry and Chemical Engineering

California Institute of Technology

1200 East California Blvd, Pasadena, California, 91125, USA.

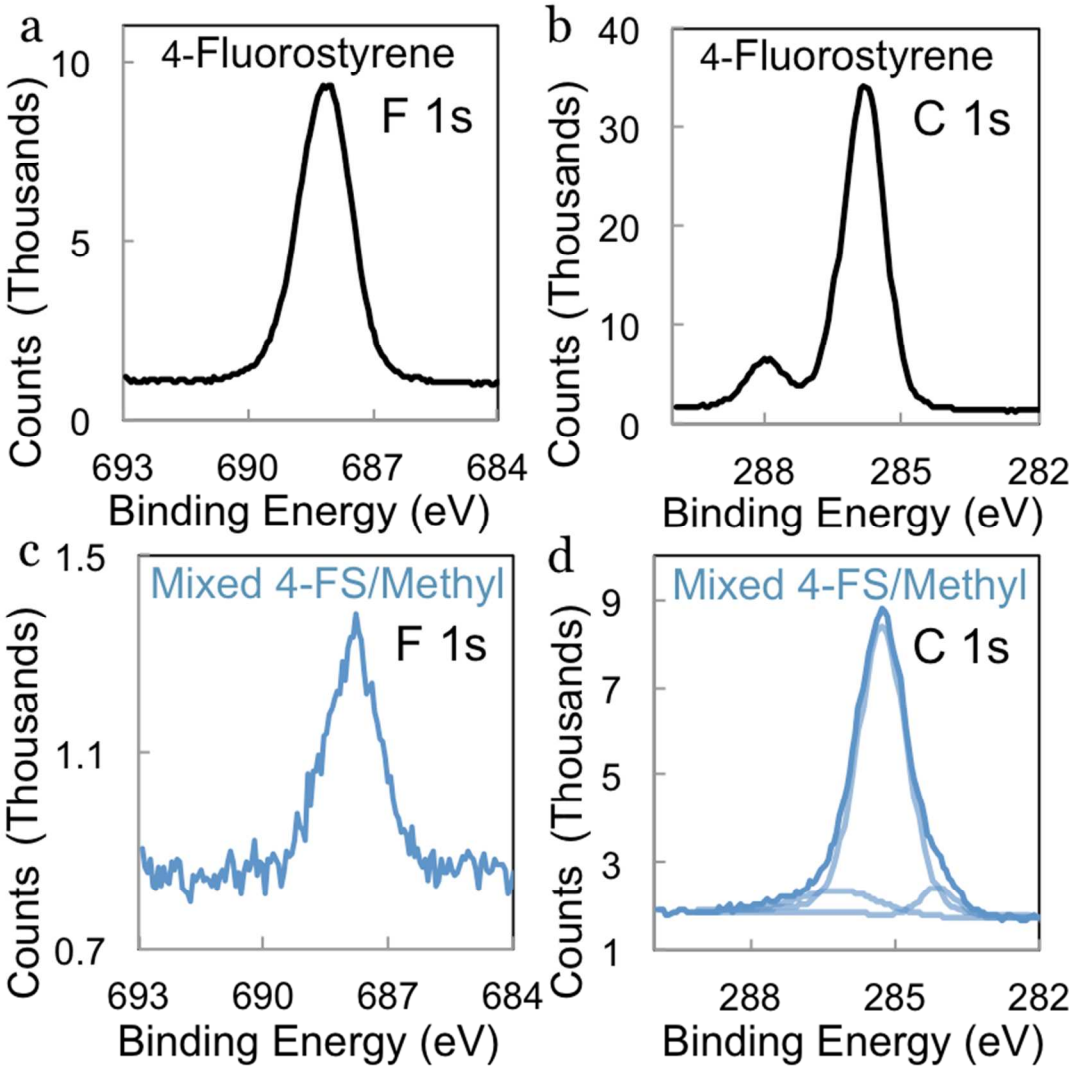
E-mail: bsb@caltech.edu, nslewis@caltech.edu, hbgray@caltech.edu.

SUPPORTING INFORMATION



SI Figure 1. Photograph of the assembled Teflon electrochemistry working electrode cell (left) and the disassembled cell (right). The working silicon electrode surface was sealed by a vitar o-ring with an area of 0.28 cm^2 when the white Teflon cell was screwed into

the stainless steel base. The back of the silicon wafer was scratched with a GaIn eutectic which makes an ohmic contact to the Si. The wafer was then attached to a Cu foil and the stainless steel base, which was then used as the contact for the working electrode to the potentiostat. The glass cell was screwed into the Teflon base, and the reference and counter electrodes were then placed in the solution.



SI Figure 2. High-resolution F 1s and C 1s XPS signals, respectively, on pure 4-fluorostyrene (a,b) and mixed 4-fluorostyrene/methyl (c,d) Si(111) surfaces.